

United States Patent [19]

Ide et al.

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[54] **ELECTRONIC THERMOMETER PROBE**

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[73] Assignee: **Terumo Kabushiki Kaisha, Tokyo, Japan**

[**] Term: **14 Years**

[21] Appl. No.: **152,580**

[22] Filed: **Feb. 5, 1988**

[30] **Foreign Application Priority Data**

Oct. 21, 1987 [JP] Japan 62-42744

[52] U.S. Cl. **D10/60**

[58] Field of Search D10/57, 60; 374/100, 374/106, 132, 151, 158, 159, 164, 170, 179, 185, 194, 208, 209; 128/236, 207.14

[56] **References Cited**

U.S. PATENT DOCUMENTS

D. 261,367 10/1981 Janson D10/60

D. 277,267 1/1985 Knute D10/60

D. 287,473 12/1986 Ueno D10/57
D. 287,829 1/1987 Osaka D10/57
D. 299,812 2/1989 Sakaguchi et al. D10/60 X
D. 300,609 4/1989 Leverty D10/60

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[57] **CLAIM**

The ornamental design for an electronic probe, as shown and described.

DESCRIPTION

FIG. 1 is a front elevational view of an electronic thermometer probe showing our new design; FIG. 2 is a top plan view, the bottom plan view being identical; FIG. 3 is a rear elevational view; FIG. 4 is a left side elevational view; FIG. 5 is a right side elevational view; and FIG. 6 is a cross-sectional view taken along line 6—6 of FIG. 1 thereof.

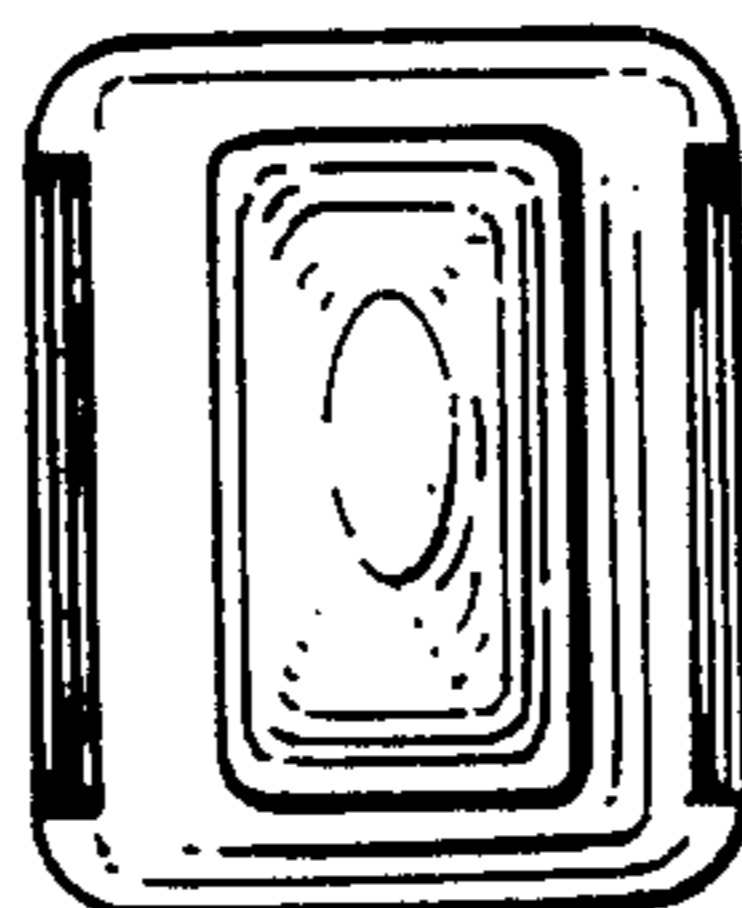


FIG. 1

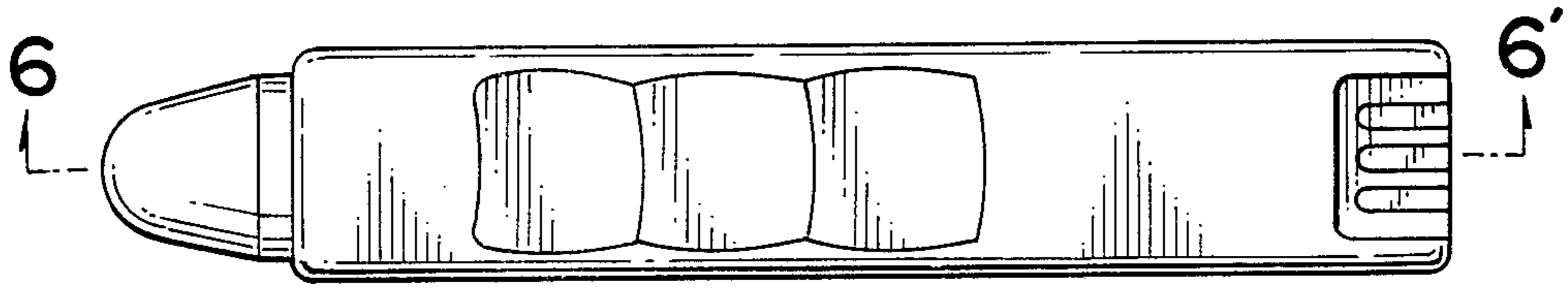


FIG. 2



FIG. 3

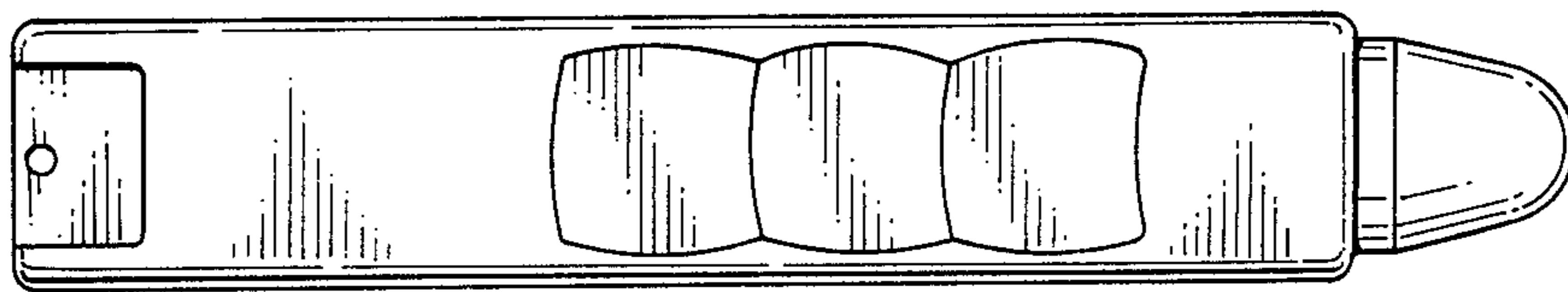


FIG. 4

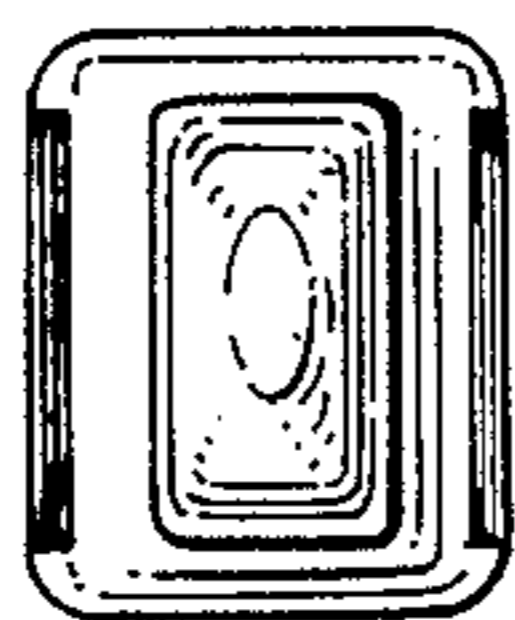


FIG. 5



FIG. 6

